

1. General description

Planar passivated Silicon Controlled Rectifier with sensitive gate in a SOT54 (TO-92) plastic package. This SCR is designed to be interfaced directly to microcontrollers, logic ICs and other low power gate trigger circuits.

2. Features and benefits

- High voltage capability
- · Planar passivated for voltage ruggedness and reliability
- Sensitive gate

3. Applications

- Ignition circuits
- Lighting ballasts
- Protection circuits
- Switched Mode Power Supplies

4. Quick reference data

Table 1. Quick reference data

Devenueter	Conditions		Mire	Ture	Mox	Unit
Parameter	Conditions			тур	wax	Unit
repetitive peak reverse voltage			-	-	600	V
average on-state current	half sine wave; T _{lead} ≤ 83 °C; <u>Fig. 1</u>		-	-	0.5	A
RMS on-state current	half sine wave; T _{lead} ≤ 83 °C; <u>Fig. 2;</u> <u>Fig. 3</u>		-	-	0.8	A
non-repetitive peak on- state current	half sine wave; T _{j(init)} = 25 °C; t _p = 10 ms; <u>Fig. 4; Fig. 5</u>		-	-	8	A
	half sine wave; T _{j(init)} = 25 °C; t _p = 8.3 ms		-	-	9	A
junction temperature			-	-	125	°C
eristics						
gate trigger current	V _D = 12 V; I _T = 10 mA; T _j = 25 °C; <u>Fig. 7</u>		-	50	200	μA
acteristics						
rate of rise of off-state voltage	V_{DM} = 402 V; T _j = 125 °C; R _{GK} = 1 kΩ; (V _{DM} = 67% of V _{DRM}); exponential waveform; Fig. 12		500	800	-	V/µs
	voltage average on-state current RMS on-state current non-repetitive peak on- state current junction temperature eristics gate trigger current cteristics rate of rise of off-state	repetitive peak reverse voltagehalf sine wave; $T_{lead} \le 83 \degree C$; Fig. 1average on-state currenthalf sine wave; $T_{lead} \le 83 \degree C$; Fig. 2; Fig. 3RMS on-state currenthalf sine wave; $T_{lead} \le 83 \degree C$; Fig. 2; Fig. 3non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 \degree C$; tp = 10 ms; Fig. 4; Fig. 5half sine wave; $T_{j(init)} = 25 \degree C$; tp = 8.3 msjunction temperatureristicsgate trigger current $V_D = 12 \ V$; $I_T = 10 \ mA$; $T_j = 25 \degree C$; Fig. 7rate of rise of off-state voltage $V_{DM} = 402 \ V$; $T_j = 125 \degree C$; $R_{GK} = 1 \ k\Omega$; ($V_{DM} = 67\% \ of \ V_{DRM}$); exponential	repetitive peak reverse voltagehalf sine wave; $T_{lead} \le 83 \ ^{\circ}C$; Fig. 1average on-state currenthalf sine wave; $T_{lead} \le 83 \ ^{\circ}C$; Fig. 2; Fig. 3RMS on-state currenthalf sine wave; $T_{lead} \le 83 \ ^{\circ}C$; Fig. 2; Fig. 3non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 \ ^{\circ}C$; $t_p = 10 \ ms; Fig. 4; Fig. 5non-repetitive peak on-state currenthalf sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ msjunction temperaturein the sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ msjunction temperaturein the sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ msgate trigger currentV_D = 12 \ V; I_T = 10 \ mA; T_j = 25 \ ^{\circ}C;Fig. 7rate of rise of off-statevoltageV_{DM} = 402 \ V; T_j = 125 \ ^{\circ}C; R_{GK} = 1 \ k\Omega;(V_{DM} = 67\% \ Of \ V_{DRM}); exponential$	repetitive peak reverse voltage	repetitive peak reverse voltagehalf sine wave; $T_{lead} \le 83 \ ^{\circ}C$; Fig. 1average on-state currenthalf sine wave; $T_{lead} \le 83 \ ^{\circ}C$; Fig. 2; Fig. 3RMS on-state current non-repetitive peak on- state currenthalf sine wave; $T_{lead} \le 83 \ ^{\circ}C$; Fig. 2; Fig. 3non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25 \ ^{\circ}C$; $t_p = 10 \ ms; Fig. 4; Fig. 5non-repetitive peak on-state currenthalf sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ msjunction temperaturegate trigger currentV_D = 12 \ V; \ I_T = 10 \ mA; \ T_j = 25 \ ^{\circ}C;Fig. 7-50gate trigger currentV_D = 12 \ V; \ I_T = 10 \ mA; \ T_j = 25 \ ^{\circ}C;Fig. 7-50rate of rise of off-statevoltageVDM = 402 V; \ T_j = 125 \ ^{\circ}C; \ R_{GK} = 1 \ k\Omega;$ (VDM = 67% of VDRM); exponential500800	repetitive peak reverse voltage600average on-state currenthalf sine wave; $T_{lead} \le 83$ °C; Fig. 1600RMS on-state current state currenthalf sine wave; $T_{lead} \le 83$ °C; Fig. 2; Fig. 30.5RMS on-state current state currenthalf sine wave; $T_{lead} \le 83$ °C; Fig. 2; Fig. 30.8non-repetitive peak on- state currenthalf sine wave; $T_{j(init)} = 25$ °C; tp = 10 ms; Fig. 4; Fig. 58junction temperature9-125gate trigger current $V_D = 12$ V; $I_T = 10$ mA; $T_j = 25$ °C; Fig. 7-50200ceteristics50200rest of rise of off-state voltage $V_{DM} = 402$ V; $T_j = 125$ °C; $R_{GK} = 1$ k Ω ; $(V_{DM} = 67\%$ of V_{DRM}); exponential500800-

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		V_{DM} = 402 V; T _j = 125 °C; (V _{DM} = 67% of V _{DRM}); exponential waveform; gate open circuit; Fig. 12	-	25	-	V/µs

5. Pinning information

Table 2. F	able 2. Pinning information						
Pin	Symbol	Description	Simplified outline	Graphic symbol			
1	А	anode		A-D-K			
2	G	gate	() (G sym037			
3	К	cathode		<i></i>			

6. Ordering information

Table 3. Ordering information

Type number	er Package				
	Name	Description	Version		
BT169G	TO-92	plastic single-ended leaded (through hole) package; 3 leads	SOT54		

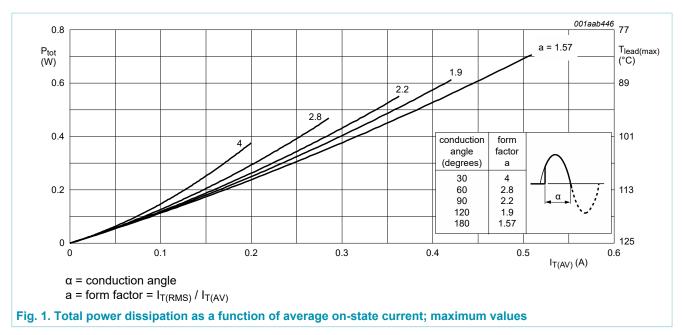
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7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

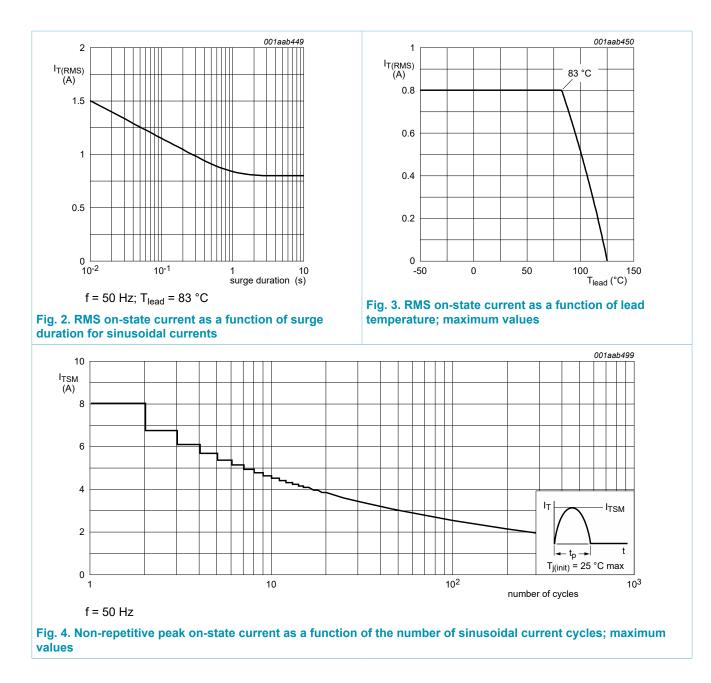
Symbol	Parameter	Conditions	Min	Max	Unit
V _{DRM}	repetitive peak off-state voltage		-	600	V
V _{RRM}	repetitive peak reverse voltage		-	600	V
I _{T(AV)}	average on-state current	half sine wave; T _{lead} ≤ 83 °C; <u>Fig. 1</u>	-	0.5	А
I _{T(RMS)}	RMS on-state current	half sine wave; T _{lead} ≤ 83 °C; <u>Fig. 2</u> ; <u>Fig. 3</u>	-	0.8	А
I _{TSM} non-repetitive peak on- state current		half sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 10 \text{ ms}$; Fig. 4; Fig. 5	-	8	А
		half sine wave; T _{j(init)} = 25 °C; t _p = 8.3 ms	-	9	А
l ² t	I ² t for fusing	t _p = 10 ms; SIN	-	0.32	A²s
dl _T /dt	rate of rise of on-state current	I _T = 2 A; I _G = 10 mA; dI _G /dt = 100 mA/μs	-	50	A/µs
I _{GM}	peak gate current		-	1	А
V _{RGM}	peak reverse gate voltage		-	5	V
P _{GM}	peak gate power		-	2	W
P _{G(AV)}	average gate power	over any 20 ms period	-	0.1	W
T _{stg}	storage temperature		-40	150	°C
Tj	junction temperature		-	125	°C



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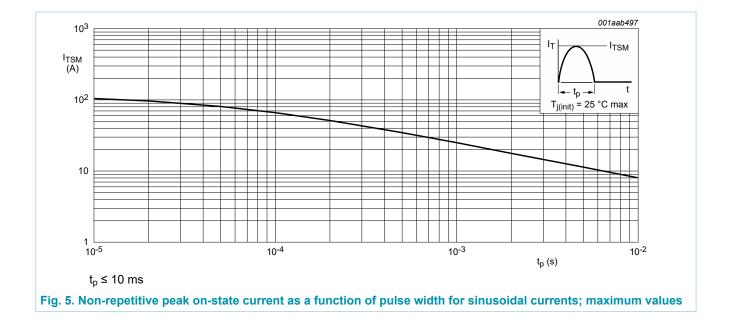
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8. Thermal characteristics

Table 5. Therma	al characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-lead)}	thermal resistance from junction to lead	Fig. 6	-	-	60	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	printed circuit board mounted: lead length = 4 mm	-	150	-	K/W

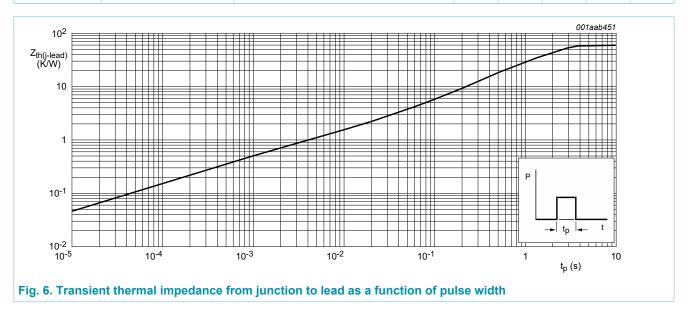


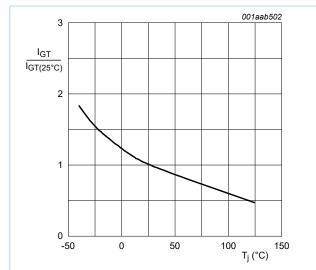
Table 5. Thermal characteristic

9. Characteristics

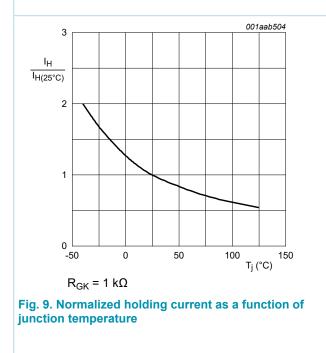
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics	· · · · · ·				
I _{GT}	gate trigger current	V _D = 12 V; I _T = 10 mA; T _j = 25 °C; <u>Fig. 7</u>	-	50	200	μA
L	latching current	V _D = 12 V; I _G = 0.5 mA; T _j = 25 °C; <u>Fig. 8</u>	-	2	6	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	2	5	mA
V _T	on-state voltage	I _T = 1.2 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.25	1.7	V
V _{GT}	gate trigger voltage	V _D = 12 V; I _T = 10 mA; T _j = 25 °C; <u>Fig. 11</u>	-	0.5	0.8	V
		V _D = 600 V; I _T = 10 mA; T _j = 125 °C; <u>Fig. 11</u>	0.2	0.3	-	V
I _D	off-state current	V_D = 600 V; $R_{GK(ext)}$ = 1 k Ω ; T_j = 125 °C	-	0.05	0.1	mA
I _R	reverse current	V_R = 600 V; T _j = 125 °C; R _{GK(ext)} = 1 k Ω	-	0.05	0.1	mA
Dynamic ch	aracteristics	· · · · · · · · · · · · · · · · · · ·	· ·	·		
dV _D /dt rate of rise voltage	rate of rise of off-state voltage	$\label{eq:VDM} \begin{array}{l} V_{DM} = 402 \; V; \; T_{j} = 125 \; ^{\circ}\text{C}; \; R_{GK} = 1 \; k\Omega; \\ (V_{DM} = 67\% \; of \; V_{DRM}); \; exponential \\ waveform; \; \underline{Fig. \; 12} \end{array}$	500	800	-	V/µs
		V_{DM} = 402 V; T _j = 125 °C; (V _{DM} = 67% of V _{DRM}); exponential waveform; gate open circuit; Fig. 12	-	25	-	V/µs
t _{gt}	gate-controlled turn-on time	$\begin{split} I_{TM} &= 2 \text{ A}; V_D = 600 \text{ V}; I_G = 10 \text{mA}; \text{d} I_G / \\ \text{d} t &= 0.1 \text{A} / \mu \text{s}; \text{T}_j = 25 ^\circ \text{C} \end{split}$	-	2	-	μs
t _q	commutated turn-off time	V_{DM} = 402 V; T _j = 125 °C; I _{TM} = 1.6 A; V_R = 35 V; (dI _T /dt) _M = 30 A/µs; dV _D / dt = 2 V/µs; R _{GK(ext)} = 1 kΩ; (V _{DM} = 67% of V _{DRM})	-	100	-	μs

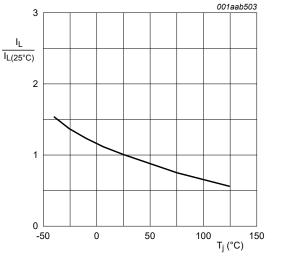
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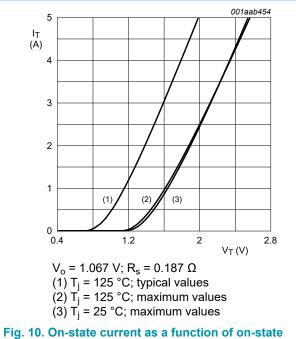








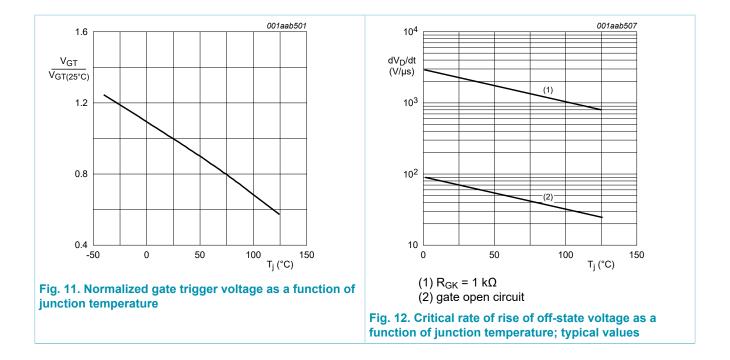




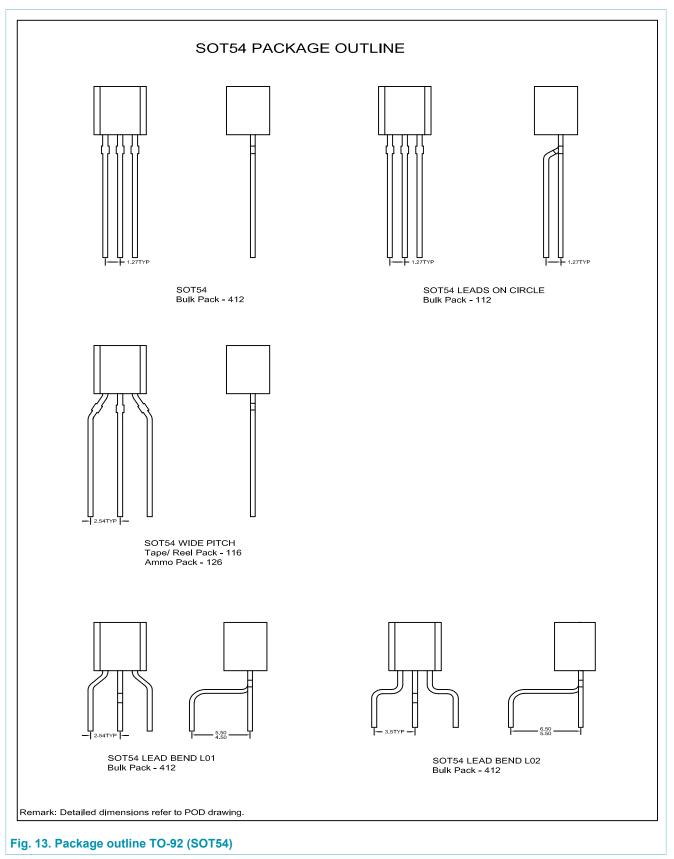
voltage

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10. Package outline



Product data sheet

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11. Legal information

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Document status [1][2]	Product status [<u>3]</u>	Definition
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Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

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